



ALPHA & OMEGA
SEMICONDUCTOR

AO7801 Dual P-Channel Enhancement Mode Field Effect Transistor

General Description

The AO7801 uses advanced trench technology to provide excellent $R_{DS(ON)}$, low gate charge, and operation with gate voltages as low as 1.8V, in the small SOT363 footprint. It can be used for a wide variety of applications, including load switching, low current inverters and low current DC-DC converters. It is ESD protected to 2KV HBM.

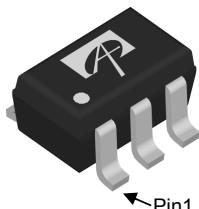
Features

V_{DS} (V) = -20V
 I_D = -0.6A (V_{GS} = -4.5V)
 $R_{DS(ON)} < 520\text{m}\Omega$ (V_{GS} = -4.5V)
 $R_{DS(ON)} < 700\text{m}\Omega$ (V_{GS} = -2.5V)
 $R_{DS(ON)} < 950\text{m}\Omega$ (V_{GS} = -1.8V)

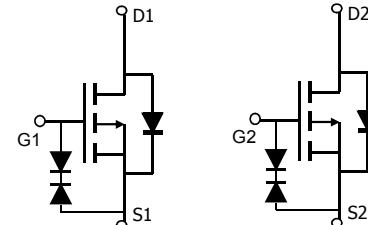
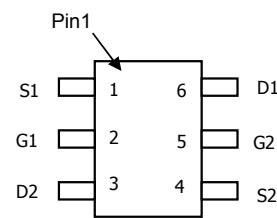
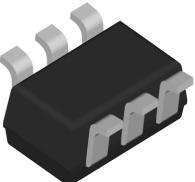


SC70-6L
(SOT-363)

Top View



Bottom View



Absolute Maximum Ratings $T_A=25^\circ\text{C}$ unless otherwise noted

Parameter	Symbol	Maximum	Units
Drain-Source Voltage	V_{DS}	-20	V
Gate-Source Voltage	V_{GS}	± 8	V
Continuous Drain Current ^A $T_A=25^\circ\text{C}$	I_D	-0.6	A
$T_A=70^\circ\text{C}$		-0.48	
Pulsed Drain Current ^B	I_{DM}	-3	
Power Dissipation ^A $T_A=25^\circ\text{C}$	P_D	0.3	W
$T_A=70^\circ\text{C}$		0.19	
Junction and Storage Temperature Range	T_J, T_{STG}	-55 to 150	°C

Thermal Characteristics

Parameter	Symbol	Typ	Max	Units
Maximum Junction-to-Ambient ^A $t \leq 10\text{s}$	$R_{\theta JA}$	360	415	°C/W
Maximum Junction-to-Ambient ^A Steady-State		400	460	°C/W
Maximum Junction-to-Lead ^C Steady-State	$R_{\theta JL}$	300	350	°C/W

Electrical Characteristics ($T_J=25^\circ\text{C}$ unless otherwise noted)

Symbol	Parameter	Conditions	Min	Typ	Max	Units
STATIC PARAMETERS						
BV_{DSS}	Drain-Source Breakdown Voltage	$I_D=-250\mu\text{A}, V_{GS}=0\text{V}$	-20			V
I_{DSS}	Zero Gate Voltage Drain Current	$V_{DS}=-16\text{V}, V_{GS}=0\text{V}$ $T_J=55^\circ\text{C}$			-1 -5	μA
I_{GSS}	Gate-Body leakage current	$V_{DS}=0\text{V}, V_{GS}=\pm 8\text{V}$			± 10	μA
$V_{\text{GS(th)}}$	Gate Threshold Voltage	$V_{DS}=V_{GS}, I_D=-250\mu\text{A}$	-0.5	-0.6	-0.9	V
$I_{\text{D(ON)}}$	On state drain current	$V_{GS}=-4.5\text{V}, V_{DS}=-5\text{V}$	-3			A
$R_{\text{DS(ON)}}$	Static Drain-Source On-Resistance	$V_{GS}=-4.5\text{V}, I_D=-0.6\text{A}$ $T_J=125^\circ\text{C}$	400	520		$\text{m}\Omega$
		$V_{GS}=-2.5\text{V}, I_D=-0.5\text{A}$	542	700		$\text{m}\Omega$
		$V_{GS}=-1.8\text{V}, I_D=-0.4\text{A}$	540	700	950	$\text{m}\Omega$
g_{FS}	Forward Transconductance	$V_{DS}=-5\text{V}, I_D=-0.6\text{A}$		1.7		S
V_{SD}	Diode Forward Voltage	$I_S=-0.5\text{A}, V_{GS}=0\text{V}$		-0.86	-1	V
I_s	Maximum Body-Diode Continuous Current				-0.4	A
DYNAMIC PARAMETERS						
C_{iss}	Input Capacitance	$V_{GS}=0\text{V}, V_{DS}=-10\text{V}, f=1\text{MHz}$		114	140	pF
C_{oss}	Output Capacitance			17		pF
C_{rss}	Reverse Transfer Capacitance			14		pF
R_g	Gate resistance	$V_{GS}=0\text{V}, V_{DS}=0\text{V}, f=1\text{MHz}$		12	17	Ω
SWITCHING PARAMETERS						
Q_g	Total Gate Charge	$V_{GS}=-4.5\text{V}, V_{DS}=-10\text{V}, I_D=-0.6\text{A}$		1.44	1.8	nC
Q_{gs}	Gate Source Charge			0.14		nC
Q_{gd}	Gate Drain Charge			0.35		nC
$t_{\text{D(on)}}$	Turn-On Delay Time	$V_{GS}=-4.5\text{V}, V_{DS}=-10\text{V}, R_L=16.7\Omega, R_{\text{GEN}}=3\Omega$		6.5		ns
t_r	Turn-On Rise Time			6.5		ns
$t_{\text{D(off)}}$	Turn-Off Delay Time			18.2		ns
t_f	Turn-Off Fall Time			5.5		ns
t_{rr}	Body Diode Reverse Recovery Time	$I_F=-0.6\text{A}, dI/dt=100\text{A}/\mu\text{s}$		10	13	ns
Q_{rr}	Body Diode Reverse Recovery Charge	$I_F=-0.6\text{A}, dI/dt=100\text{A}/\mu\text{s}$		3		nC

A: The value of R_{gJA} is measured with the device mounted on 1 in² FR-4 board with 2oz. Copper, in a still air environment with $T_A=25^\circ\text{ C}$. The value in any given application depends on the user's specific board design. The current rating is based on the $t \leq 10\text{s}$ thermal resistance rating.

B: Repetitive rating, pulse width limited by junction temperature.

C: The R_{gJA} is the sum of the thermal impedance from junction to lead R_{gJL} and lead to ambient.

D: The static characteristics in Figures 1 to 6,12,14 are obtained using 80 μs pulses, duty cycle 0.5% max.

E: These tests are performed with the device mounted on 1 in² FR-4 board with 2oz. Copper, in a still air environment with $T_A=25^\circ\text{ C}$. The SOA curve provides a single pulse rating.

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TYPICAL ELECTRICAL AND THERMAL CHARACTERISTICS

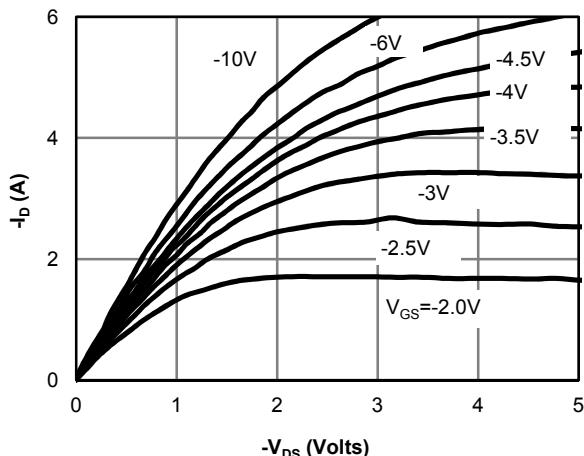


Fig 1: On-Region Characteristics

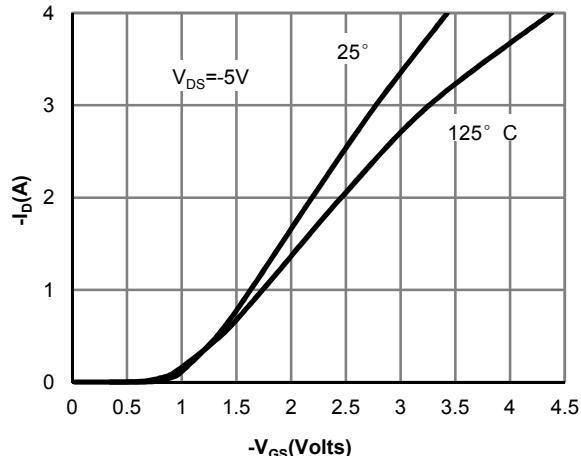


Figure 2: Transfer Characteristics

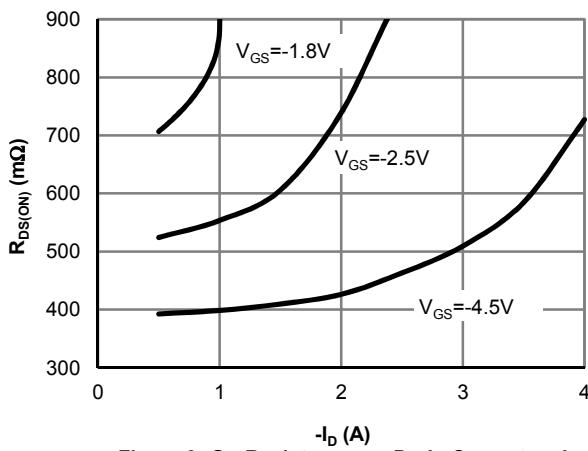


Figure 3: On-Resistance vs. Drain Current and Gate Voltage

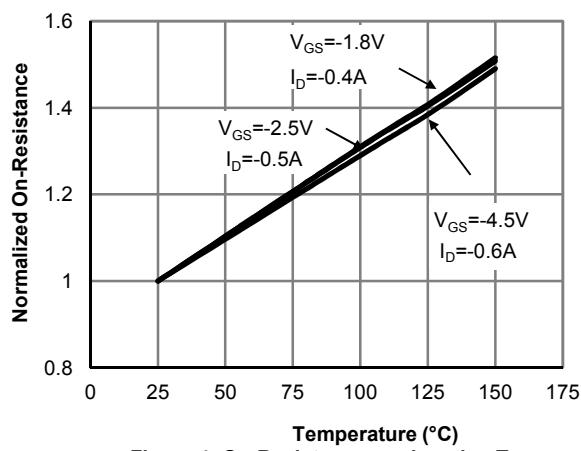


Figure 4: On-Resistance vs. Junction Temperature

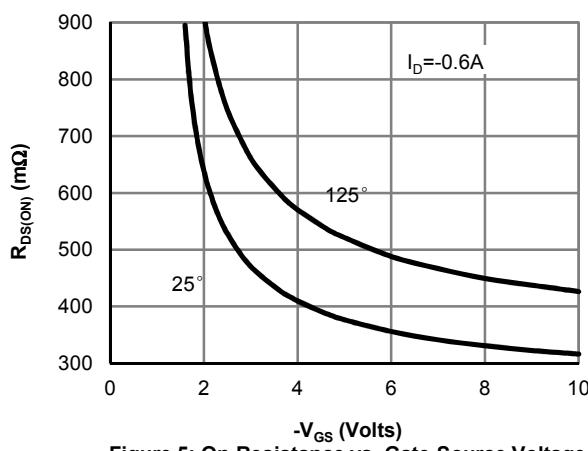


Figure 5: On-Resistance vs. Gate-Source Voltage

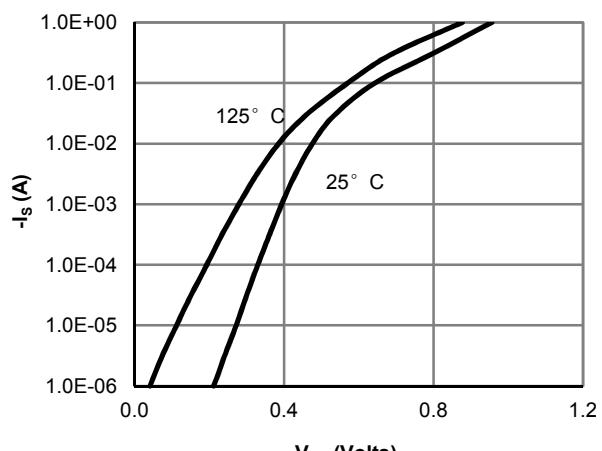


Figure 6: Body-Diode Characteristics

TYPICAL ELECTRICAL AND THERMAL CHARACTERISTICS

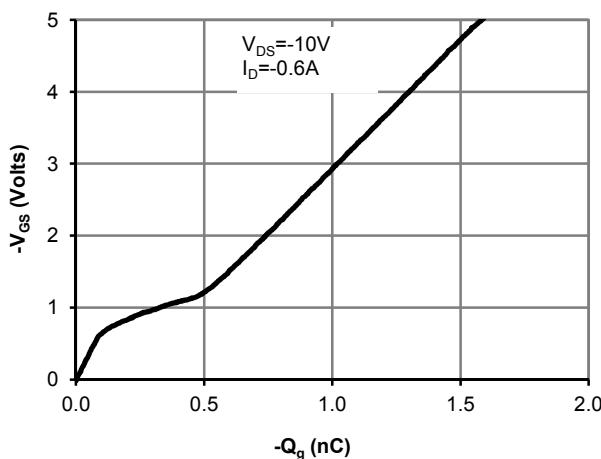


Figure 7: Gate-Charge Characteristics

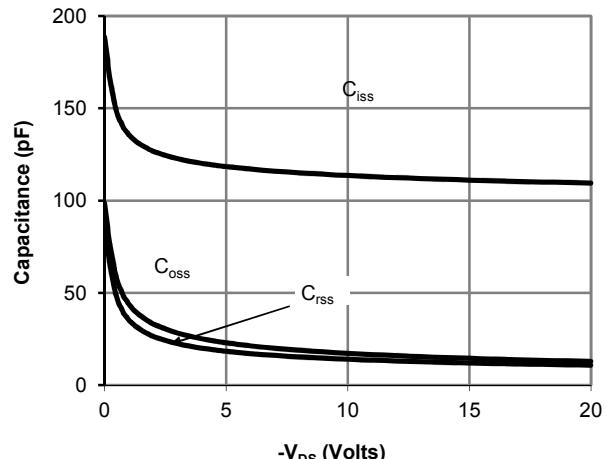


Figure 8: Capacitance Characteristics

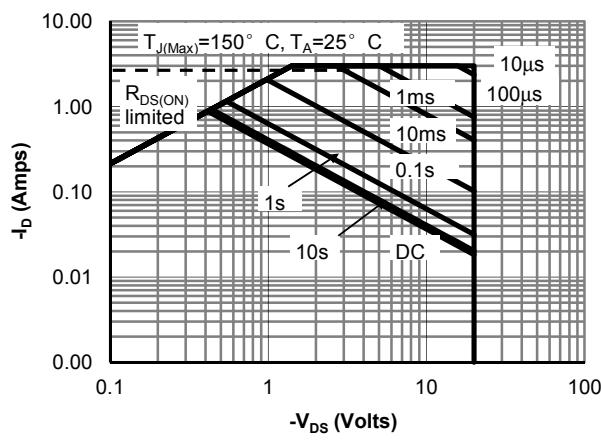


Figure 9: Maximum Forward Biased Safe Operating Area (Note E)

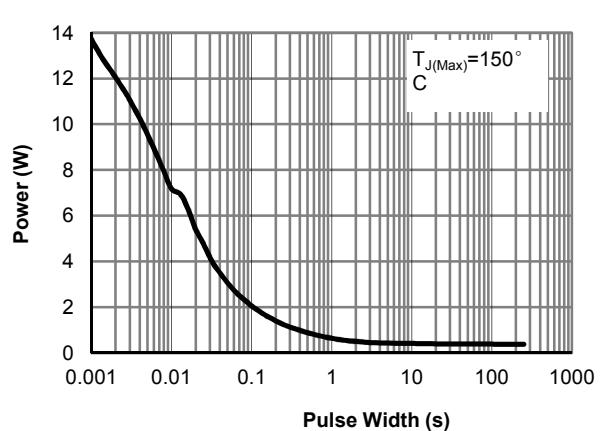


Figure 10: Single Pulse Power Rating Junction-to-Ambient (Note E)

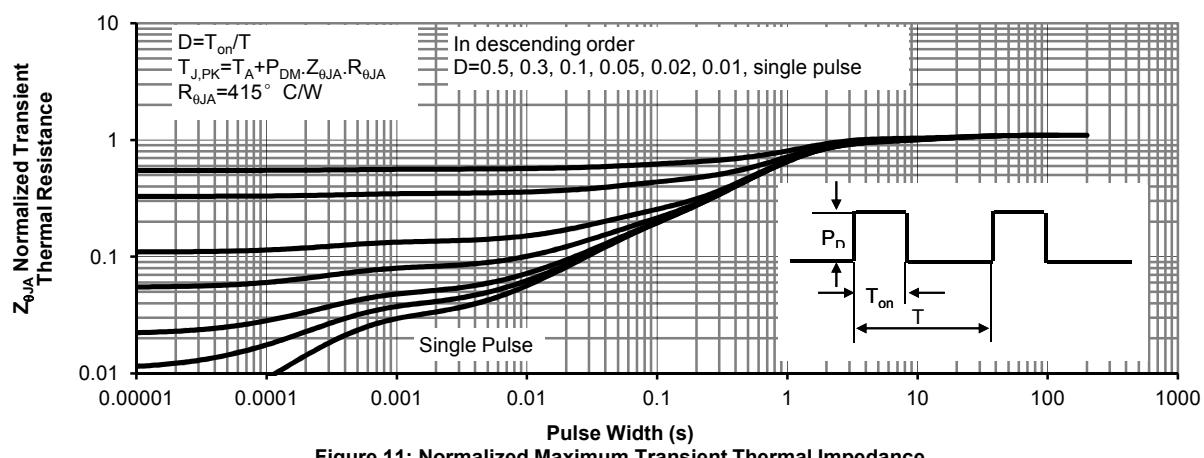
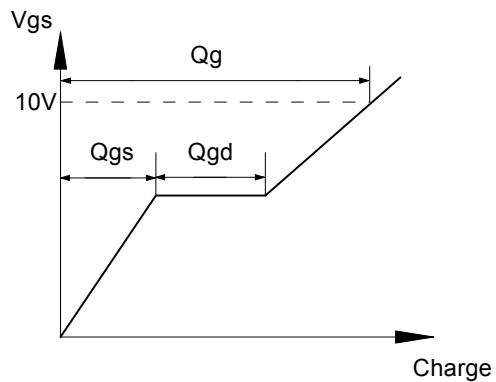
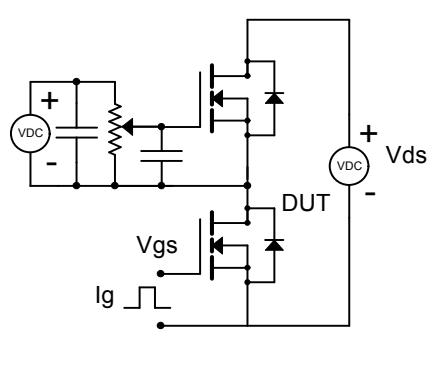
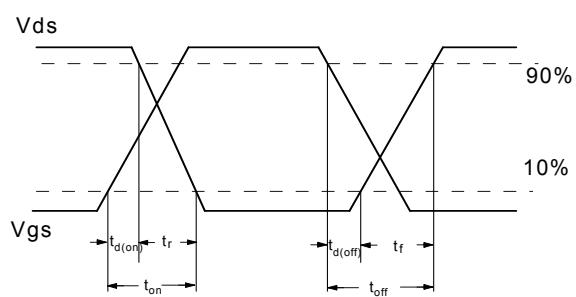
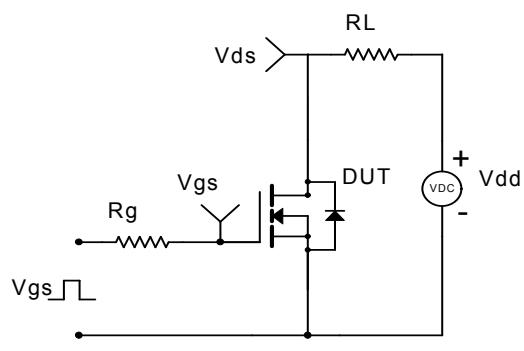


Figure 11: Normalized Maximum Transient Thermal Impedance

Gate Charge Test Circuit & Waveform



Resistive Switching Test Circuit & Waveforms



Diode Recovery Test Circuit & Waveforms

